


<b>Search Notes</b>  	<b>Application/Control No.</b>  10811926	<b>Applicant(s)/Patent Under Reexamination</b>  ONO ET AL.
	<b>Examiner</b>  ANISH SIKRI	<b>Art Unit</b>  2143

SEARCHED			
Class	Subclass	Date	Examiner
371	68	4/14/08	as

SEARCH NOTES		
Search Notes	Date	Examiner
East Image and Keyword search in USPAT, US-PGPUB, DERWENT, EPO, JPO and IBM_TDB (see attached search strategy)	4/14/08	AS
Inventor name and Assignee search in PALM ExPO and EAST	4/14/08	AS
17 and ((multiple adj2 (module\$2 or node\$2)) near3 (data adj4 process\$5))	4/14/08	AS

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner